

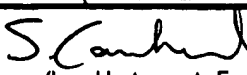


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/607,740		DELANEY ET AL.	
	Examiner		Art Unit	
	Quynh H. Nguyen		2642	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
379		229			379	230	88.17	221.08	221.12	
INTERNATIONAL CLASSIFICATION										
H	0	4	M	7/00						
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				/						
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Quynh H. Nguyen 9/8/05 (Assistant Examiner) (Date)		 AHMAD F. MATAR SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2000 (Primary Examiner) (Date) 9/18/05	Total Claims Allowed: 31	
 (Legal Instruments Examiner) (Date) 9/20/05			O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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